

<b>Notice of References Cited</b>	Application/Control No. 10/743,172	Applicant(s)/Patent Under Reexamination KAWASE ET AL.	
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**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2004/0224231	11-2004	Fujimoto et al.	429/232
*	B US-6,242,132	06-2001	Neudecker et al.	429/218.1
	C US-			
	D US-			
	E US-			
	F US-			
	G US-			
	H US-			
	I US-			
	J US-			
	K US-			
	L US-			
	M US-			

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N JP 11-135115	05-1999	Japan	Akagi et al.	H01M 4/36
	O				
	P				
	Q				
	R				
	S				
	T				

**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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